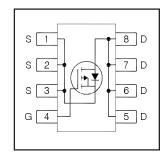


# IRF9310PbF

## HEXFET® Power MOSFET

V <sub>DS</sub>	-30	V
<b>R</b> <sub>DS(on) max</sub> (@V <sub>GS</sub> = 10V)	4.6	$m\Omega$
<b>I</b> <sub>D</sub> (@T <sub>A</sub> = 25°C)	-20	Α





## **Applications**

• Charge and Discharge Switch for Notebook PC Battery Application

#### **Features and Benefits**

#### **Features**

Low $R_{DSon}$ ( $\leq 4.6m\Omega$ )	
Industry-Standard SO8 Package	
RoHS Compliant Containing no Lead, no Bromide and no Halogen	

#### **Resulting Benefits**

	Lower Conduction Losses
results in	Multi-Vendor Compatibility
$\Rightarrow$	Environmentally Friendlier

Orderable part number	Package Type	Standard Pack		Note
		Form	Quantity	
IRF9310PbF	SO8	Tube/Bulk	95	
IRF9310TRPbF	SO8	Tape and Reel	4000	

**Absolute Maximum Ratings** 

	Parameter	Max.	Units	
V <sub>DS</sub>	Drain-to-Source Voltage	-30	V	
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	-20		
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	-16	А	
I <sub>DM</sub>	Pulsed Drain Current ①	-160		
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation ④	2.5	w	
P <sub>D</sub> @T <sub>A</sub> = 70°C	Power Dissipation 4	1.6	VV	
	Linear Derating Factor	0.02	W/°C	
T <sub>J</sub>	Operating Junction and	-55 to + 150	°C	
T <sub>STG</sub>	Storage Temperature Range			



# Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	-30			٧	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.020		V/°C	Reference to 25°C, I <sub>D</sub> = -1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		3.9	4.6	0	V <sub>GS</sub> = -10V, I <sub>D</sub> = -20A ③
	Static Drain-to-Source On-Resistance		5.8	6.8	mΩ	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -16A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	-1.3	-1.8	-2.4	V	V V I 100··A
$\Delta V_{GS(th)}$	Gate Threshold Voltage Coefficient		-5.8		mV/°C	$V_{DS} = V_{GS}, I_D = -100\mu A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			-1.0	μА	$V_{DS} = -24V, V_{GS} = 0V$
				-150	μA	$V_{DS} = -24V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	_		-100		$V_{GS} = -20V$
	Gate-to-Source Reverse Leakage			100	nA	V <sub>GS</sub> = 20V
gfs	Forward Transconductance	39			S	$V_{DS} = -10V, I_{D} = -16A$
$Q_g$	Total Gate Charge ®		58		nC	$V_{DS} = -15V$ , $V_{GS} = -4.5V$ , $I_{D} = -16A$
Q <sub>g</sub>	Total Gate Charge ®		110	165		$V_{GS} = -10V$
$Q_{gs}$	Gate-to-Source Charge ®		17		nC	$V_{DS} = -15V$
$Q_{gd}$	Gate-to-Drain Charge ®		28		1	$I_D = -16A$
$R_G$	Gate Resistance ©		2.8		Ω	
t <sub>d(on)</sub>	Turn-On Delay Time		25			$V_{DD} = -15V, V_{GS} = -4.5V$ ③
t <sub>r</sub>	Rise Time		47		ns	$I_{D} = -1.0A$
t <sub>d(off)</sub>	Turn-Off Delay Time		65		ris	$R_G = 1.8\Omega$
t <sub>f</sub>	Fall Time		70			See Figs. 20a &20b
C <sub>iss</sub>	Input Capacitance		5250			$V_{GS} = 0V$
Coss	Output Capacitance		1300		pF	$V_{DS} = -15V$
C <sub>rss</sub>	Reverse Transfer Capacitance		880		]	f = 1.0MHz

#### **Avalanche Characteristics**

	Parameter	Тур.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy ②		630	mJ
I <sub>AR</sub>	Avalanche Current ①		-16	A

# **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			-2.5		MOSFET symbol
	(Body Diode)			-2.5	A	showing the
I <sub>SM</sub>	Pulsed Source Current			-160	^	integral reverse
	(Body Diode) ①			-100		p-n junction diode.
$V_{\text{SD}}$	Diode Forward Voltage			-1.2	٧	$T_J = 25^{\circ}C$ , $I_S = -2.5A$ , $V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		71	107	ns	$T_J = 25^{\circ}C$ , $I_F = -2.5A$ , $V_{DD} = -24V$
$Q_{rr}$	Reverse Recovery Charge		12	18	nC	di/dt = 100A/µs ③

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units	
$R_{\theta JL}$	Junction-to-Drain Lead ©		20	0C/M	
$R_{\theta JA}$	Junction-to-Ambient @		50	°C/W	

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^{\circ}C$ , L = 4.9 mH,  $R_G = 25\Omega$ ,  $I_{AS} = -16 \text{A}$ .
- $\ensuremath{\mathfrak{G}}$  When mounted on 1 inch square copper board.
- © For DESIGN AID ONLY, not subject to production testing.

2 www.irf.com

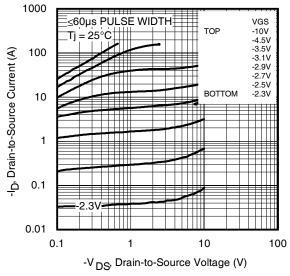


Fig 1. Typical Output Characteristics

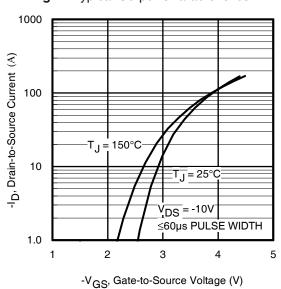
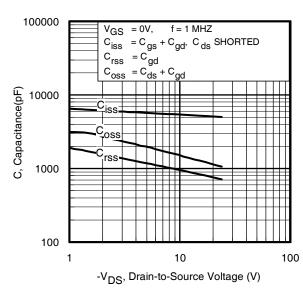


Fig 3. Typical Transfer Characteristics



**Fig 5.** Typical Capacitance vs.Drain-to-Source Voltage www.irf.com

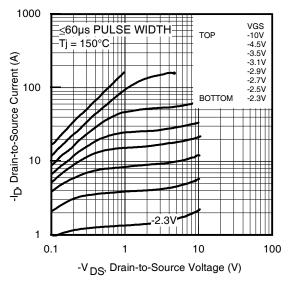


Fig 2. Typical Output Characteristics

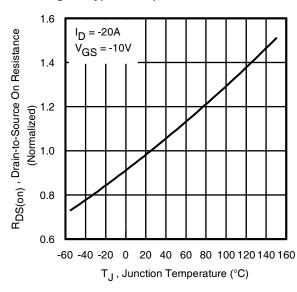


Fig 4. Normalized On-Resistance vs. Temperature

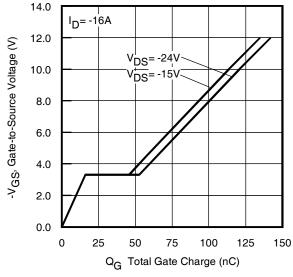


Fig 6. Typical Gate Charge vs.Gate-to-Source Voltage

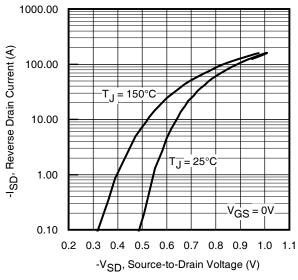
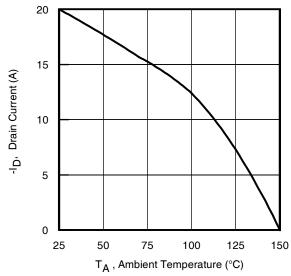


Fig 7. Typical Source-Drain Diode Forward Voltage



**Fig 9.** Maximum Drain Current vs. Ambient Temperature

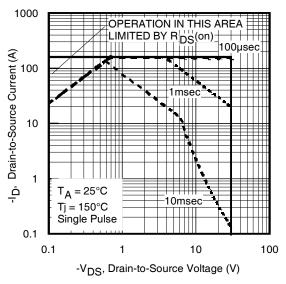


Fig 8. Maximum Safe Operating Area

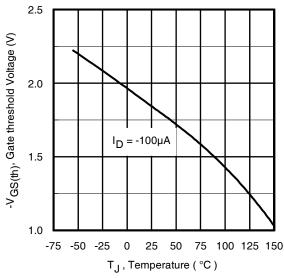


Fig 10. Threshold Voltage vs. Temperature

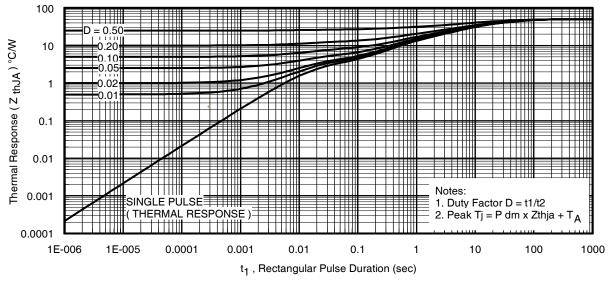


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

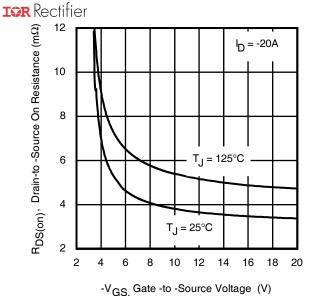


Fig 12. On-Resistance vs. Gate Voltage

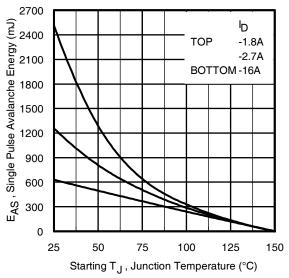


Fig 14. Maximum Avalanche Energy vs. Drain Current

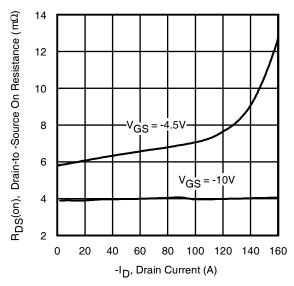


Fig 13. Typical On-Resistance vs. Drain Current

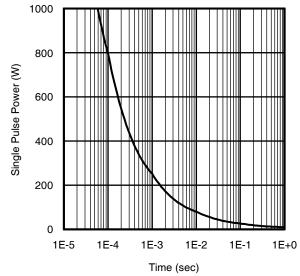
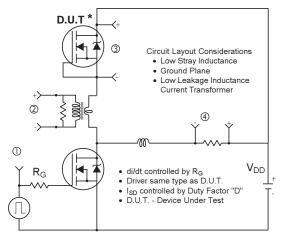
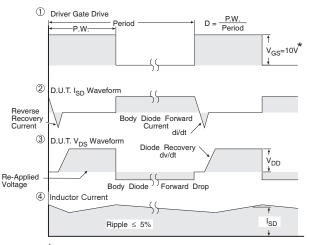


Fig 16. Typical Power vs. Time



<sup>\*</sup> Reverse Polarity of D.U.T for P-Channel



\* V<sub>GS</sub> = 5V for Logic Level Devices

Fig 17. Diode Reverse Recovery Test Circuit for P-Channel HEXFET® Power MOSFETs

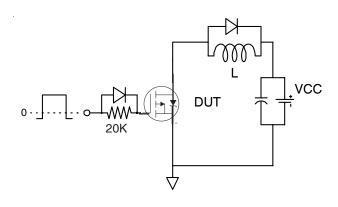


Fig 18a. Gate Charge Test Circuit

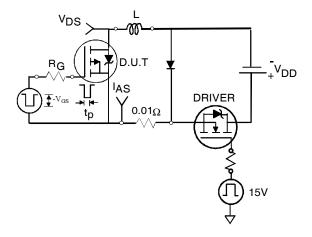


Fig 19a. Unclamped Inductive Test Circuit

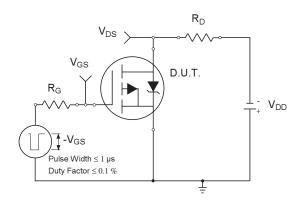


Fig 20a. Switching Time Test Circuit

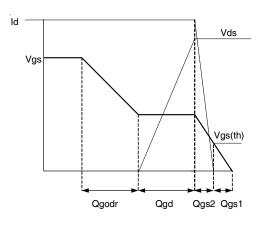


Fig 18b. Gate Charge Waveform

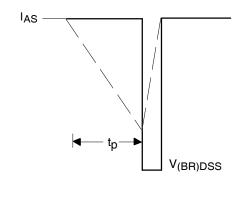


Fig 19b. Unclamped Inductive Waveforms

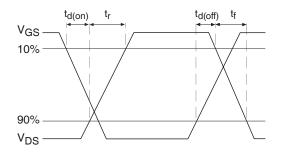
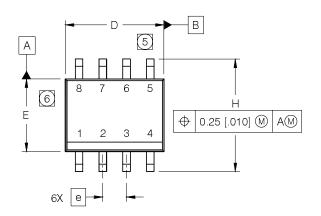


Fig 20b. Switching Time Waveforms

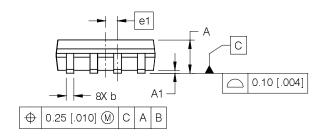
6 www.irf.com

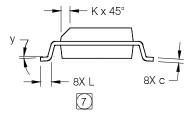
# SO-8 Package Outline(Mosfet & Fetky)

Dimensions are shown in milimeters (inches)



DIM	INCHES		MILLIM	ETERS
DIIVI	MIN	MAX	MIN	MAX
Α	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
С	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
е	.050 B	ASIC	1.27 B	ASIC
e 1	.025 BASIC		0.635 E	BASIC
Н	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
У	O°	8°	0°	8°





#### NOTES:

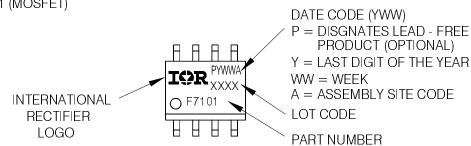
- 1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
- 2. CONTROLLING DIMENSION: MILLIMETER
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
- (5) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 [.006].
- (6) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 [.010].
- (7) DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.

# 

7

# SO-8 Part Marking Information

EXAMPLE: THIS IS AN IRF7101 (MOSFET)

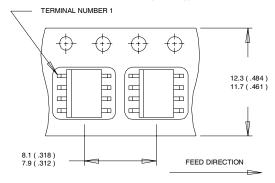


Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

# IRF9310PbF

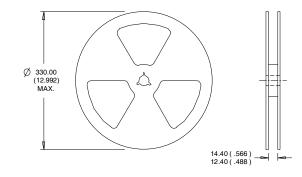


SO-8 Tape and Reel (Dimensions are shown in milimeters (inches))



#### NOTES:

- CONTROLLING DIMENSION : MILLIMETER.
- ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- OUTLINE CONFORMS TO EIA-481 & EIA-541.



1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

#### Qualification Information<sup>†</sup>

Qualification level	Consumer ††  (per JEDEC JESD47F <sup>†††</sup> guidelines)		
Qualification level			
Moisture Sensitivity Level	SO-8 (per JEDEC J-STD-020E		
RoHS Compliant		Yes	

- + Qualification standards can be found at International Rectifier's web site http://www.irf.com/product-info/reliability
- †† Higher qualification ratings may be available should the user have such requirements. Please contact your International Rectifier sales representative for further information: http://www.irf.com/whoto-call/salesrep/
- **†††** Applicable version of JEDEC standard at the time of product release.

**Revision History** 

Date	Comment		
3/18/2010	Figure 16, Power vs. Time curve is modified and updated. All other parameters remain unchanged.		

Data and specifications subject to change without notice.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

TAC Fax: (310) 252-7903